AURCET - 2013 SYLLABUS TEST NO. 77 :: INSTRUMENTATION ENGINEERING

(100 MARKS)

Basics of Circuits and Measurement Systems: Kirchoff's laws, mesh and nodal Analysis. Circuit theorems. One-port and two-port Network Functions. Static and dynamic characteristics of Measurement Systems. Error and uncertainty analysis. Statistical analysis of data and curve fitting.

Transducers, Mechanical Measurement and Industrial Instrumentation: Resistive, Capacitive, Inductive and piezoelectric transducers and their signal conditioning. Measurement of displacement, velocity and acceleration (translational and rotational), force, torque, vibration and shock. Measurement of pressure, flow, temperature and liquid level. Measurement of pH, conductivity, viscosity and humidity.

Analog Electronics: Characteristics of diode, BJT, JFET and MOSFET. Diode circuits. Transistors at low and high frequencies, Amplifiers, single and multi-stage. Feedback amplifiers. Operational amplifiers, characteristics and circuit configurations. Instrumentation amplifier. Precision rectifier. V-to-I and I-to-V converter. Op-Amp based active filters. Oscillators and signal generators.

Digital Electronics: Combinational logic circuits, minimization of Boolean functions. IC families, TTL, MOS and CMOS. Arithmetic circuits. Comparators, Schmitt trigger, timers and mono-stable multi-vibrator. Sequential circuits, flip-flops, counters, shift registers. Multiplexer, S/H circuit. Analog-to-Digital and Digital-to-Analog converters. Basics of number system. Microprocessor applications, memory and input-output interfacing. Microcontrollers.

Signals, Systems and Communications: Periodic and aperiodic signals. Impulse response, transfer function and frequency response of first- and second order systems. Convolution, correlation and characteristics of linear time invariant systems. Discrete time system, impulse and frequency response. Pulse transfer function. IIR and FIR filters. Amplitude and frequency modulation and demodulation. Sampling theorem, pulse code modulation. Frequency and time division multiplexing. Amplitude shift keying, frequency shift keying and pulse shift keying for digital modulation.

Electrical and Electronic Measurements: Bridges and potentiometers, measurement of R,L and C. Measurements of voltage, current, power, power factor and energy. A.C & D.C current probes. Extension of instrument ranges. Q-meter and waveform analyzer. Digital voltmeter and multi-meter. Time, phase and frequency measurements. Cathode ray oscilloscope. Serial and parallel communication. Shielding and grounding.

Control Systems and Process Control: Feedback principles. Signal flow graphs. Transient Response, steady-state-errors. Routh and Nyquist criteria. Bode plot, root loci. Time delay systems. Phase and gain margin. State space representation of systems. Mechanical, hydraulic and pneumatic system components. Synchro pair, servo and step motors. On-off, cascade, P, P-I, P-I-D, feed forward and derivative controller, Fuzzy controllers.

Analytical, Optical and Biomedical Instrumentation: Mass spectrometry. UV, visible and IR spectrometry. X-ray and nuclear radiation measurements. Optical sources and detectors, LED, laser, Photo-diode, photo-resistor and their characteristics. Interferometers, applications in metrology. Basics of fiber optics. Biomedical instruments, EEG, ECG and EMG. Clinical measurements. Ultrasonic transducers and Ultrasonography. Principles of Computer Assisted Tomography.